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	Substitute for Fo				Application Number	10/549,950		
6	INFORM	ATION D	ISC	LOSURE	Filing Date	September 20, 2005		
	STATEMENT BY APPLICANT			PLICANT	First Named Inventor	Charles H. Winter et al.		
SÉ)			Group Art Unit	2818		
Ar.		e as many sheets	as ne	ecessary)	Examiner Name	Unknown		
	RAREN	1	of	3	Attorney Docket Number	WSU 0200 PUSA		

	U.S. PATENT DOCUMENTS								
Examiner Initials	Cite No.1	U.S. PATENT D	OCUMENT Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
		6,887,151	В2	Leen et al.	05/03/2005				
		6,887,297	B2	Winter et al.	05/03/2005				
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	FOREIGN PATENT DOCUMENTS									
Examiner	Cite		Foreign Patent Doo	Kind Code⁵	Name of Patentee or	Date of Publication of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant			
Initials	No.1	No.¹	Office ³	Number ⁴	(if known)	Applicant of Cited Document	MM-DD-YYYY	Figures Appear		
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Examiner Signature	/Anthony Zimmer/	Date Considered	09/25/2008
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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Substitute for	Form 1449B/PTO			Complete if Known					
				Application Number	10/549,950				
			CLOSURE	Filing Date	September 20, 2005				
SIAIE	MENT BY	AP	PLICANT	First Named Inventor	Charles H. Winter et al.				
				Group Art Unit	2818				
	(use as many sh	eets as	necessary)	Examiner Name	Unknown				
Sheet	2	of	3	Attorney Docket Number	WSU 0200 PUSA				
	OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS								
Include name of the author (in item (book, magazine, journal, so				CAPITAL LETTERS), title of the art erial, symposium, catalog, etc.), dat blisher, city and/or country where pul	e, page(s), volume-issue number(s),	T²			
		Pa	rticles of Gold a	Effect on the Lattice and Platinum", C. Sol 1985, pgs. 487-494					
			"Dependence of Lattice Parameters", J. Woltersdorf et al., SURFACE SCIENCE, pgs. 65-69						
		wi	th Alkali Atoms",	tions in Stripped Atoms Isoelectronic , S.N. Ray, James E. Rodgers & T.P. Das, SOCIETY, Volume 13, Number 6, June 1976					
		Co	•	all Particles of Lead and Indium", C.J. PHYSICS F - METAL PHYSICS, Volume 2, 1972,					
Eckert, J.C. Holze				f Nanocrystalline Aluminum Powders", J. r, C.C. Ahn, Z. Fu and W.L. Johnson, LS, Vol. 2, 1983, pgs. 407-413					
		Pa	rticles of Tin",	ce of the Melting Poi C.R.M. Wronski, BRIT January to December					
		an	d Theory", K.T. N	F Polycrystalline Thi Miller & F.F. Lange, . 1, Jan. 1990, pgs.	JOURNAL OF MATERIALS				
		Ko	orgel & Donald Fit	cdered nanocrystal Th zmaurice, Physical Rev April 1998, pgs. 3531	/IEW LETTERS, Volume				
		М.	D. Drory & M.S. H	Decohesion of Thin Fi Hu, Journal of Materials C/October 1988, pgs.	RESEARCH, Volume 3,				
		Ме	tallization", Hir	for Ultralarge Scale cohiko Murakami et al , 17(5), Sep/Oct 199	., JOURNAL OF VACUUM				
"Chemical Vapor Depo Metallization", Ala MATERIAL RESEARCH SOCITY			etallization", Ala	ain E. Kaloyeros & Mi	tion of Copper for Multilevel E. Kaloyeros & Michael A. Fury, JLLETIN, Volume XVIII, Number 6, June				

Examiner	/Anthony Zimmer/	Date	09/25/2008
Signature	*	Considered	

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				Group Art Unit	2818			
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Sheet	Sheet 3 of 3		3	Attorney Docket Number	WSU 0200 PUSA			
	OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS							
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		wi Su Ph	th the Size of Sr arface-Phonon inst	mall Particles, on th tability Model", M. V	Variation of the melting Temperature hall Particles, on the Basis of a hability Model", M. Wautelet, JOURNAL OF BICS, Volume 24, Number 3, 14 March 1991,			
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